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(12) **United States Design Patent**
Devlin et al.

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(54) **OFFSET PROBE THERMOMETER**

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(73) Assignee: **Chaney Instrument Company**, Lake Geneva, WI (US)

(**) Term: **14 Years**

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(22) Filed: **Mar. 21, 2001**

(51) **LOC (7) Cl.** **10-04**
(52) **U.S. Cl.** **D10/57**
(58) **Field of Search** D10/57; D7/653, D7/683; 30/129, 142, 147, 148, 150, 322, 323; 294/55.5, 61; 374/141, 155, 184, 208–210

(56) **References Cited**

U.S. PATENT DOCUMENTS

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* cited by examiner

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(74) *Attorney, Agent, or Firm*—Michael Best & Friedrich, LLC

(57) **CLAIM**

The ornamental design for a offset probe thermometer, as shown.

DESCRIPTION

FIG. **1** is a front perspective view of the offset probe thermometer of the present invention;

FIG. **2** is a right side elevation view of the offset probe thermometer shown in FIG. **1**, the left side elevation view being a mirror image thereof;

FIG. **3** is a front elevation view of the offset probe thermometer of FIG. **1**;

FIG. **4** is a top plan view of the offset probe thermometer shown in FIG. **1**;

FIG. **5** is a bottom plan view of the offset probe thermometer shown in FIG. **1**; and,

FIG. **6** is a back plan view of the offset probe thermometer shown in FIG. **2**.

1 Claim, 2 Drawing Sheets

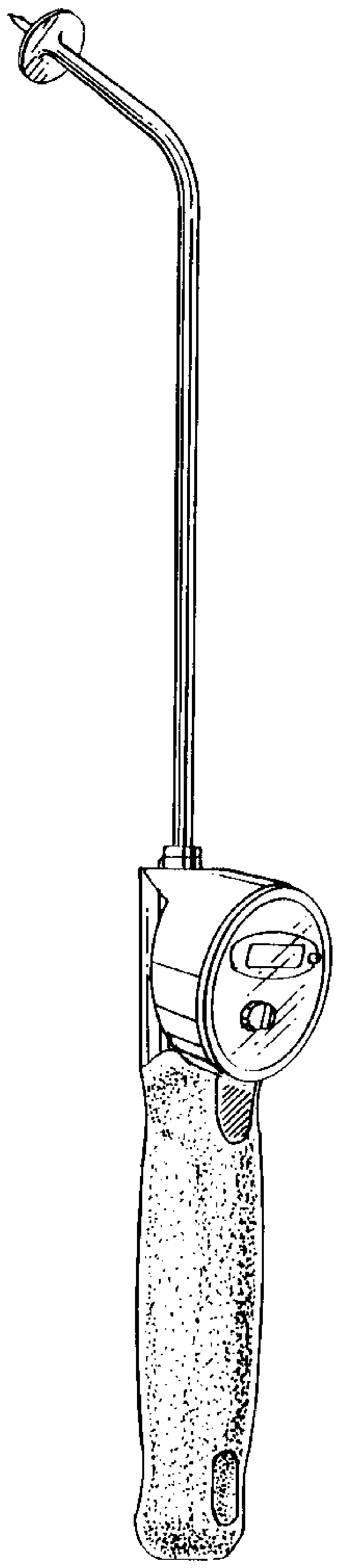

FIG. 1

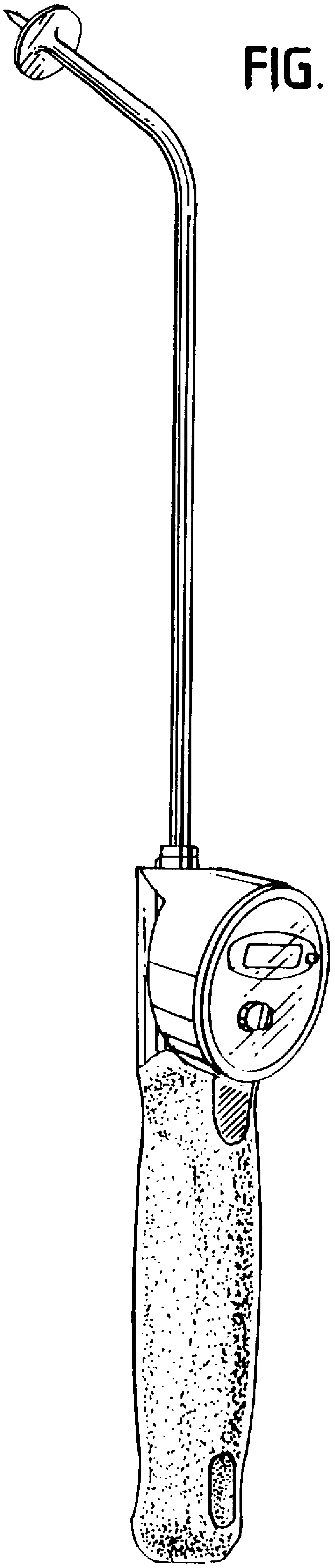

FIG. 2

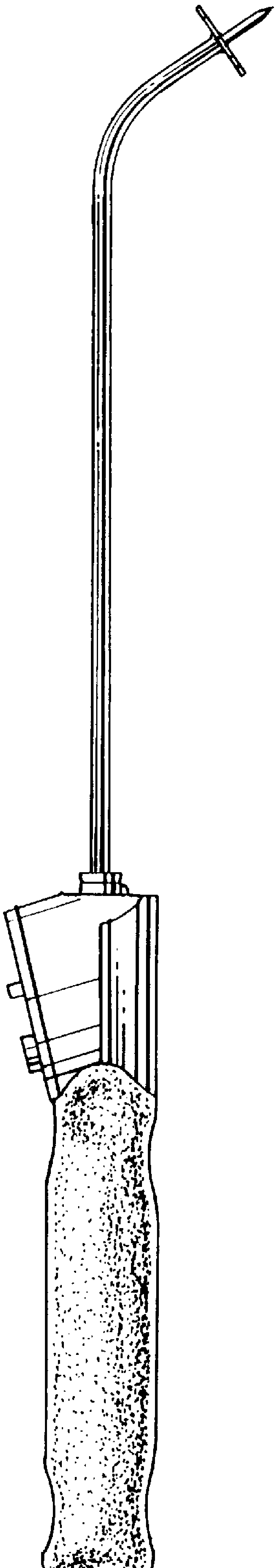

FIG. 3

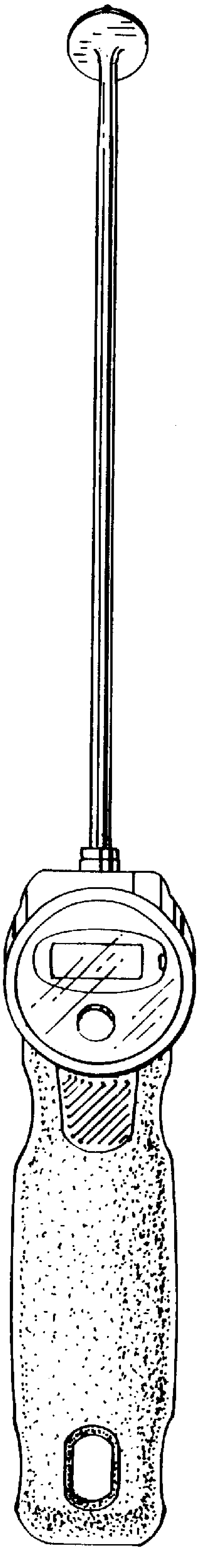

FIG. 4

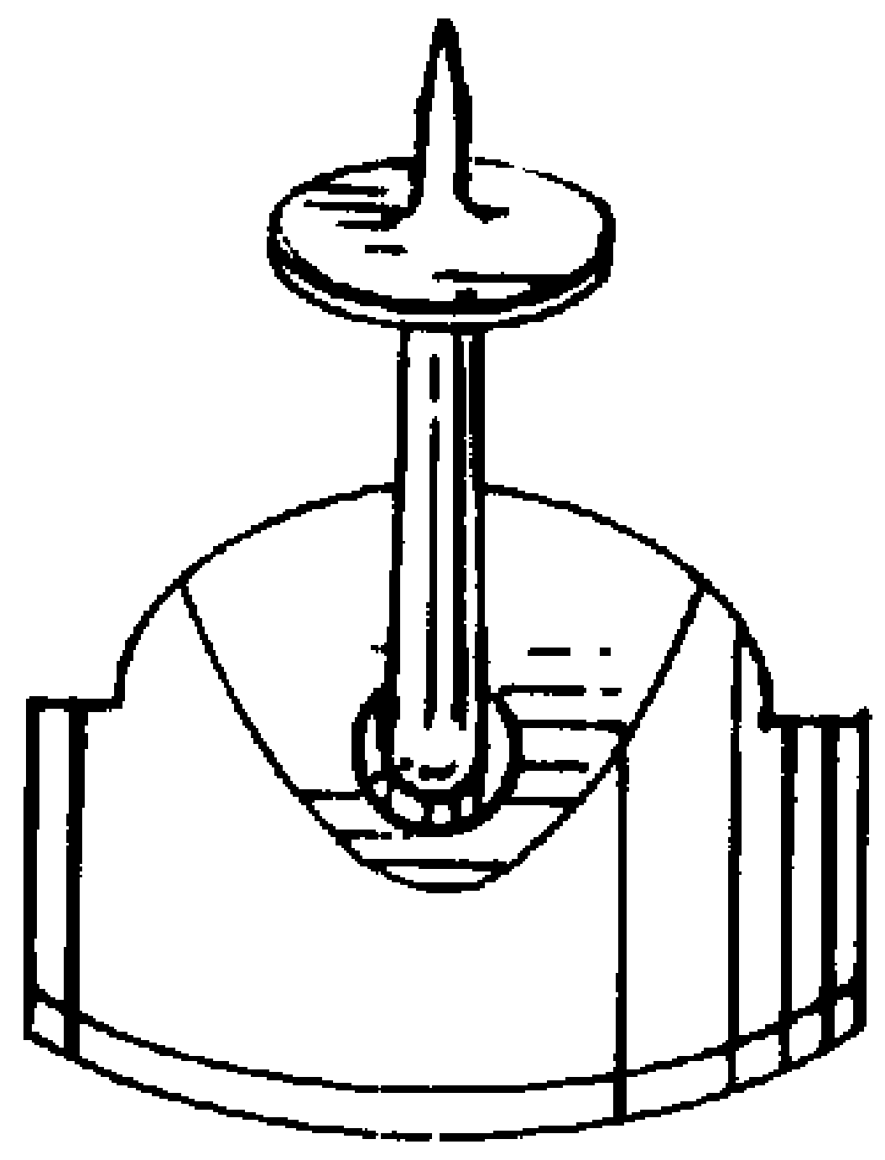

FIG. 5

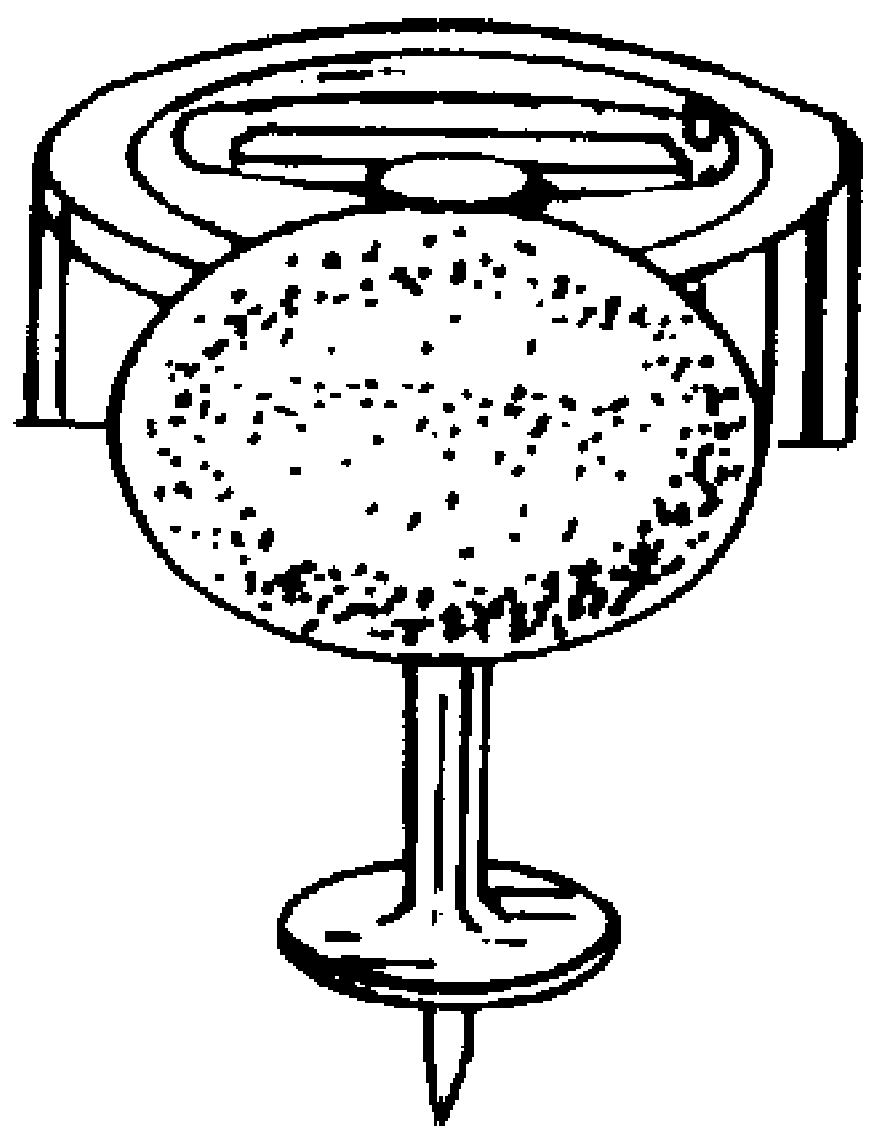

FIG. 6